

Notice of References Cited	Application/Control No. 10/710,308	Applicant(s)/Patent Under Reexamination BONALLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,245,329	09-1993	Gokcebay, Asil T.	340/5.33
	B	US-5,677,953	10-1997	Dolphin, Janet L.	705/51
	C	US-5,869,822	02-1999	Meadows et al.	235/380
	D	US-5,987,155	11-1999	Dunn et al.	382/116
	E	US-6,268,788	07-2001	Gray, Robert J.	340/5.2
	F	US-6,269,348	07-2001	Pare et al.	705/39
	G	US-2001/0053239	12-2001	Takhar, Harinder S.	382/124
	H	US-2002/0062249	05-2002	Iannacci, Gregory Fx	705/14
	I	US-2002/0062284	05-2002	KAWAN, JOSEPH C.	705/43
	J	US-2002/0066784	06-2002	Segal et al.	235/381
	K	US-2002/0095587	07-2002	Doyle et al.	713/186
	L	US-2002/0097142	07-2002	Janiak et al.	340/5.53
	M	US-2002/0140542	10-2002	Prokoski et al.	340/5.52

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0163421	11-2002	Wang et al.	340/5.83
	B	US-2002/0178063	11-2002	Gravelle et al.	705/17
	C	US-2002/0191816	12-2002	Maritzen et al.	382/115
	D	US-2003/0086591	05-2003	Simon, Rudy	382/115
	E	US-2003/0112120	06-2003	K., Seifert Mark	340/5.53
	F	US-2003/0149661	08-2003	Mitchell et al.	705/39
	G	US-2003/0150911	08-2003	Joseph, Joseph	235/382
	H	US-2003/0226041	12-2003	Palmer et al.	713/202
	I	US-2003/0229793	12-2003	McCall et al.	713/186
	J	US-2004/0020982	02-2004	Hoffman et al.	235/379
	K	US-2004/0021552	02-2004	Koo, Hong-Sik	340/5.53
	L	US-2004/0041021	03-2004	Nugent, Paul F. JR.	235/383
	M	US-2004/0041690	03-2004	Yamagishi, Junichi	340/005.52

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0084542	05-2004	DeYoe et al.	236/049.3
	B	US-2004/0131237	07-2004	Machida, Akihiro	382/124
	C	US-2004/0133787	07-2004	Doughty et al.	713/186
	D	US-2004/0149827	08-2004	Zuili, Patrick	235/439
	E	US-2004/0155101	08-2004	Royer et al.	235/379
	F	US-2004/0195314	10-2004	Lee, Ki Deak	235/380
	G	US-2004/0199469	10-2004	Barillova et al.	705/044
	H	US-2004/0208343	10-2004	Golden et al.	382/110
	I	US-2004/0257196	12-2004	Kotzin, Michael D.	340/005.52
	J	US-2005/0001711	01-2005	Doughty et al.	340/005.74
	K	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
	L	US-2005/0018658	01-2005	Ikeda et al.	370/352
	M	US-2005/0033992	02-2005	Inabe, Takeshi	713/202

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0054438	03-2005	Rothschild et al.	463/029
	B	US-2005/0065872	03-2005	Moebs et al.	705/038
	C	US-2005/0087597	04-2005	Gotfried et al.	235/382
	D	US-2005/0091325	04-2005	Kuwana et al.	709/206
	E	US-2005/0102524	05-2005	Haala, Catherine A.	713/186
	F	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
	G	US-2005/0139669	06-2005	Arnouse, Michael	235/440
	H	US-2002/0043566	04-2002	Goodman et al.	235/492
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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